

Attorney's Docket No. 005819.P001

PATENT

11000 U.S. PRO
09/955641
09/18/01

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In Re Patent Application of:)
Jack Zezhong Peng) Examiner: Not Yet Assigned *2H*
Application No.: New Application) Art Unit: Not Yet Assigned *Prior Art*
Filed: Herewith)
For: SEMICONDUCTOR MEMORY)
CELL AND MEMORY ARRAY)
USING A BREAKDOWN PHENOMENA)
IN AN ULTRA-THIN DIELECTRIC)

Commissioner for Patents
Washington, D.C. 20231

INFORMATION DISCLOSURE STATEMENT

Sir:

Enclosed is a copy of Information Disclosure Citation Form PTO-1449 together with copies of the documents cited on that form. It is respectfully requested that the cited documents be considered and that the enclosed copy of Information Disclosure Citation Form PTO-1449 be initialed by the Examiner to indicate such consideration and a copy thereof returned to applicant(s).

Pursuant to 37 C.F.R. § 1.97, the submission of this Information Disclosure Statement is not to be construed as a representation that a search has been made and is not to be construed as an admission that the information cited in this statement is material to patentability.

Pursuant to 37 C.F.R. § 1.97, this Information Disclosure Statement is being submitted under one of the following (as indicated by an "X" to the left of the appropriate paragraph):

XXX 37 C.F.R. §1.97(b).

 37 C.F.R. §1.97(c). If so, then enclosed with this Information Disclosure Statement is one of the following:

 A statement pursuant to 37 C.F.R. §1.97(e) or

 A check for \$240.00 for the fee under 37 C.F.R. § 1.17(p).

 37 C.F.R. §1.97(d). If so, then enclosed with this Information Disclosure Statement are the following:

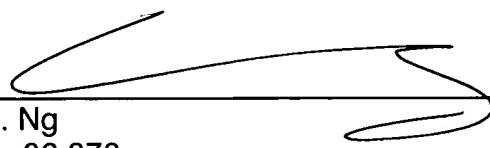
- (1) A statement pursuant to 37 C.F.R. §1.97(e);
- (2) A petition requesting consideration of the Information Disclosure Statement; and
- (3) A check for \$ _____ for the fee under 37 C.F.R. §1.17(i) for submission of the Information Disclosure Statement.

If there are any additional charges, please charge Deposit Account No. 02-2666.

Respectfully submitted,

BLAKELY, SOKOLOFF, TAYLOR & ZAFMAN LLP

Dated: 9/18, 2001



Chun M. Ng
Reg. No. 36,878

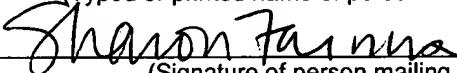
12400 Wilshire Blvd.
Seventh Floor
Los Angeles, CA 90025-1026
(206) 292-8600

I hereby certify that this correspondence is being deposited with the United States Postal Service as first class mail with sufficient postage in an envelope addressed to the Assistant Commissioner for Patents, Washington, D. C. 20231 on September 18, 2001.

(Date of Deposit)

Sharon E. Farnus

(Typed or printed name of person mailing correspondence)



(Signature of person mailing correspondence)

Please type a plus sign (+) inside this box

4

Under the Paperwork Reduction Act of 1995, no persons are required to respond to a collection of information unless it contains a valid OMB control number.

U.S. PATENT DOCUMENTS

FOREIGN PATENT DOCUMENTS

Examiner Initials *		Foreign Patent Document			Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Translation? Yes/No
		Office or Country	Number	Date			

OTHER DOCUMENTS

Examiner Initials *	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published (if known).	Translation? Yes/No
	MIRANDA, ENRIQUE et al; Analytic Modeling of Leakage Current Through Multiple Breakdown Paths in SiO ₂ Films; 39th Annual International Reliability Physics Symposium; Orlando, FL 2001	
	LOMBARDO, S. et al; Softening of Breakdown in Ultra-Thin Gate Oxide nMOSFET's at Low Inversion Layer Density; 39th Annual International Reliability Physics Symposium; Orlando, FL 2001	
	WU, E.W. et al; Voltage-Dependent Voltage-Acceleration of Oxide Breakdown for Ultra-Thin Oxides; IEEE, 2000.	
	RASRAS, MAHMOUD et al; Substrate Hole Current Origin After Oxide Breakdown; IEEE, 2000.	
	SUNE, JORDI et al.; Post Soft Breakdown Conduction in SiO ₂ Gate Oxides; IEEE, 2000.	

Examiner Signature		Date Considered	
-----------------------	--	--------------------	--

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.